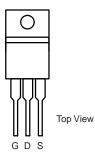


IPP26CNE8N G-VB Datasheet N-Channel 80 V (D-S) MOSFET

PRODUCT SUMMARY				
V _{DS}	80	V		
$R_{DS(on)}$ $V_{GS} = 10$ V	7	mΩ		
$R_{DS(on)}$ $V_{GS} = 4.5$ V	9	mΩ		
I _D	100	А		
Configuration	Single			





FEATURES

- Trench Power MOSFET
- 100 % $\rm R_g$ and UIS Tested

APPLICATIONS

- Primary Side Switching
- Synchronous Rectification
- DC/AC Inverters
- LED Backlighting



ABSOLUTE MAXIMUM RATINGS (T _A = 25 °C, unless	s otherwise no	oted)	
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	80	V
Gate-Source Voltage		V _{GS}	± 20	v
Continuous Drain Current (T _J = 150 °C)	T _C = 25 °C		100ª	
	T _C = 70 °C		85 ^a	
	T _A = 25 °C	I _D	28.6 ^{b, c}	
	T _A = 70 °C		24.9 ^{b, c}	
Pulsed Drain Current (t = 100 µs)	I _{DM}	350	A	
Continuous Source-Drain Diode Current	T _C = 25 °C	I _S	80 ^a	
	T _A = 25 °C		4.5 ^{b, c}	
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	30	
Single Pulse Avalanche Energy	L = 0.1 MH	E _{AS}	45	mJ
Maximum Power Dissipation	T _C = 25 °C		180	W
	T _C = 70 °C	P _D	120	
	T _A = 25 °C		5 ^{b, c}	
	T _A = 70 °C		3.2 ^{b, c}	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	ാം
Soldering Recommendations (Peak Temperature		260		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Marian and Institute to Amelian ta	$t \le 10 \text{ sec}$	R _{thJA}	15	18	°C/W	
Maximum Junction-to-Ambient ^a	Steady State		40	50		
Maximum Junction-to-Case		R _{thJC}	0.85	1.1		

Notes

- a. Package limited.
- b. Surface mounted on 1" x 1" FR4 board.

c. t = 10 s.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static	_			1	<u> </u>		
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_{D} = 250 \mu A$	80			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$			37			
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 6.1		mV/°C	
Gate-Source Threshold Voltage	V _{GS(th})	V _{DS} = V _{GS} , I _D = 250 μA	2.0		3.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
-		$V_{DS} = 80 \text{ V}, V_{GS} = 0 \text{ V}$			1	μA	
Zero Gate Voltage Drain Current	IDSS	V _{DS} = 80 V, V _{GS} = 0 V, T _J = 55 °C			10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	85			А	
		$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 20 \text{ A}$		7			
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 6 V, I _D = 15 A		7.5		mΩ	
	. ,	V _{GS} = 4.5 V, I _D = 10 A		9			
Forward Transconductance ^a	g _{fs}	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 20 \text{ A}$		60		S	
Dynamic ^b				•	•	•	
Input Capacitance	C _{iss}			3855		pF	
Output Capacitance	C _{oss}	V_{DS} = 40 V, V_{GS} = 0 V, f = 1 MHz		1120			
Reverse Transfer Capacitance	C _{rss}			376			
		$V_{DS} = 40 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$		35.5			
Total Gate Charge	Qg	$V_{DS} = 40 \text{ V}, V_{GS} = 6 \text{ V}, I_D = 10 \text{ A}$		22			
				18		nC	
Gate-Source Charge	Q _{gs}	$V_{DS} = 40 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$		5.3			
Gate-Drain Charge	Q _{gd}			7.3			
Output Charge	Q _{oss}	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}$		57	86		
Gate Resistance	Rg	f = 1 MHz	0.5	1.3	2	Ω	
Turn-On Delay Time	t _{d(on)}			12	24		
Rise Time	t _r	$V_{DD} = 40 \text{ V}, \text{ R}_{L} = 4 \Omega$		8	16]	
Turn-Off DelayTime	t _{d(off)}	$I_D \cong 10 \text{ Å}, V_{\text{GEN}} = 10 \text{ V}, R_g = 1 \Omega$		32	64		
Fall Time	t _f			7	14		
Turn-On Delay Time	t _{d(on)}			14	28	ns	
Rise Time	t _r	$V_{DD} = 40 \text{ V}, \text{ R}_{L} = 4 \Omega$		11	22		
Turn-Off DelayTime	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{GEN} = 6.0 \text{ V}, R_g = 1 \Omega$		30	60		
Fall Time	t _f			8	16		
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			75	A	
Pulse Diode Forward Current (t = 100 μ s)	I _{SM}				150	A	
Body Diode Voltage	V _{SD}	I _S = 5 A		0.76	1.1	V	
Body Diode Reverse Recovery Time	t _{rr}			38	75	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	L = 10.4 dl/dt = 100.4/m T = 05.90		36	70	nC	
Reverse Recovery Fall Time	t _a	$I_F = 10 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^\circ\text{C}$		19			
Reverse Recovery Rise Time	t _b			19		ns	

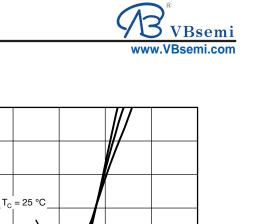
Notes

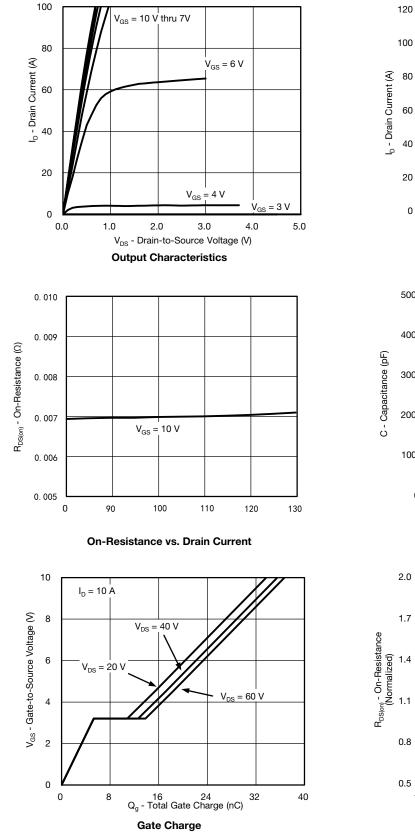
a. Pulse test; pulse width \leq 300 µs, duty cycle \leq 2 %.

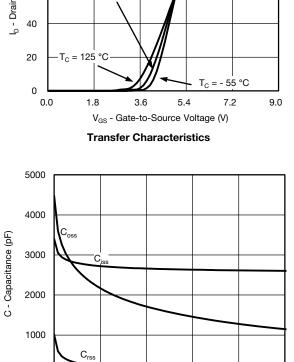
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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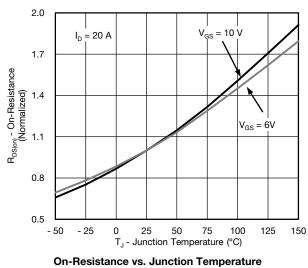




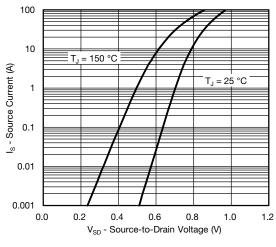




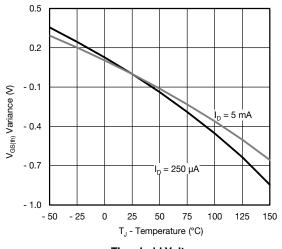
V_{DS} - Drain-to-Source Voltage (V)



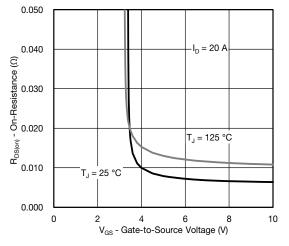




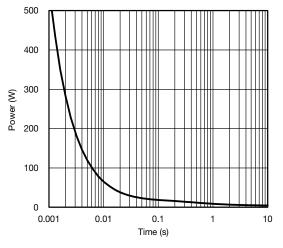
Source-Drain Diode Forward Voltage



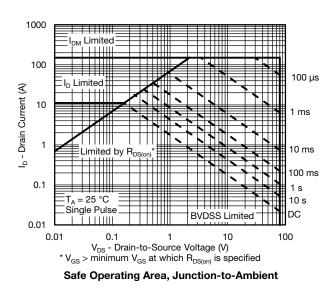




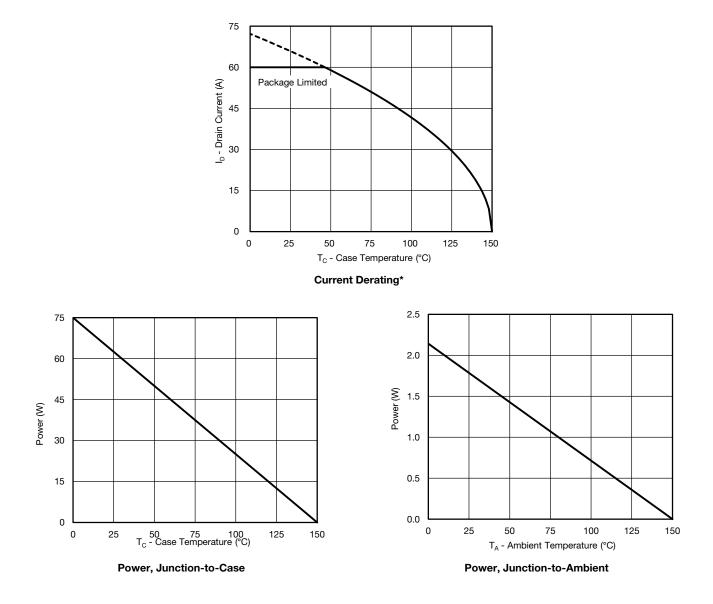
On-Resistance vs. Gate-to-Source Voltage



Single Pulse Power, Junction-to-Ambient

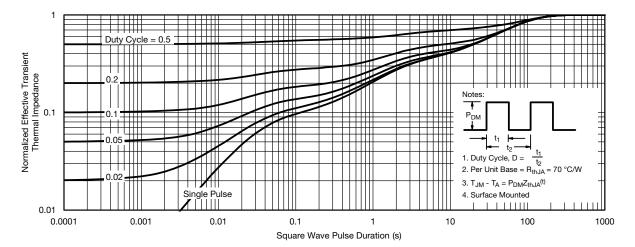




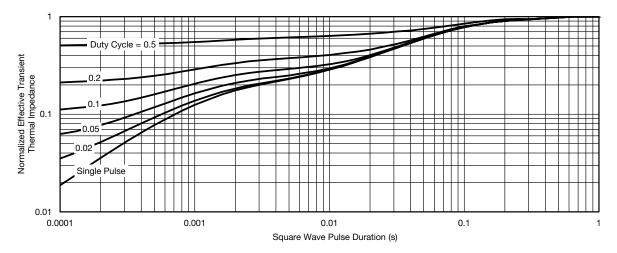


* The power dissipation P_D is based on $T_{J(max.)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





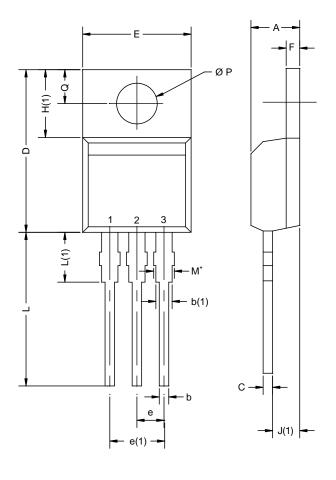
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case



TO-220AB



	MILLIMETERS		INC	HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471					

Notes

 * M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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